

Compact Model for Multiple Independent Gates Ambipolar Devices

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Compact Model for Multiple Independent Gates Ambipolar Devices / Piccinini, Gianluca; Graziano, Mariagrazia; Frache, Stefano. - ELETTRONICO. - (2013). (Intervento presentato al convegno Functionality-Enhanced Devices Workshop tenutosi a Lausanne, Svizzera nel 25 March).

*Availability:*

This version is available at: 11583/2511688 since:

*Publisher:*

EPFL

*Published*

DOI:

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# Compact Model for Multiple Independent Gates Ambipolar Devices



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**Motivation:** Ambipolarity is often suppressed by processing steps; It can be exploited to enhance logic functionality Natural evolution of FinFE  
**Novel approach is needed to tackle complex structures**

## Multiple Gates vs Multi-Gates

In this context, Multiple Gates  $\neq$  Multi-Gate

GAA are Multi-Gate devices, but do not necessarily feature MultipleGates

Present work is about Multiple Independent Multi-Gate devices

Nanoarray-based structures can benefit, as well, of this approach

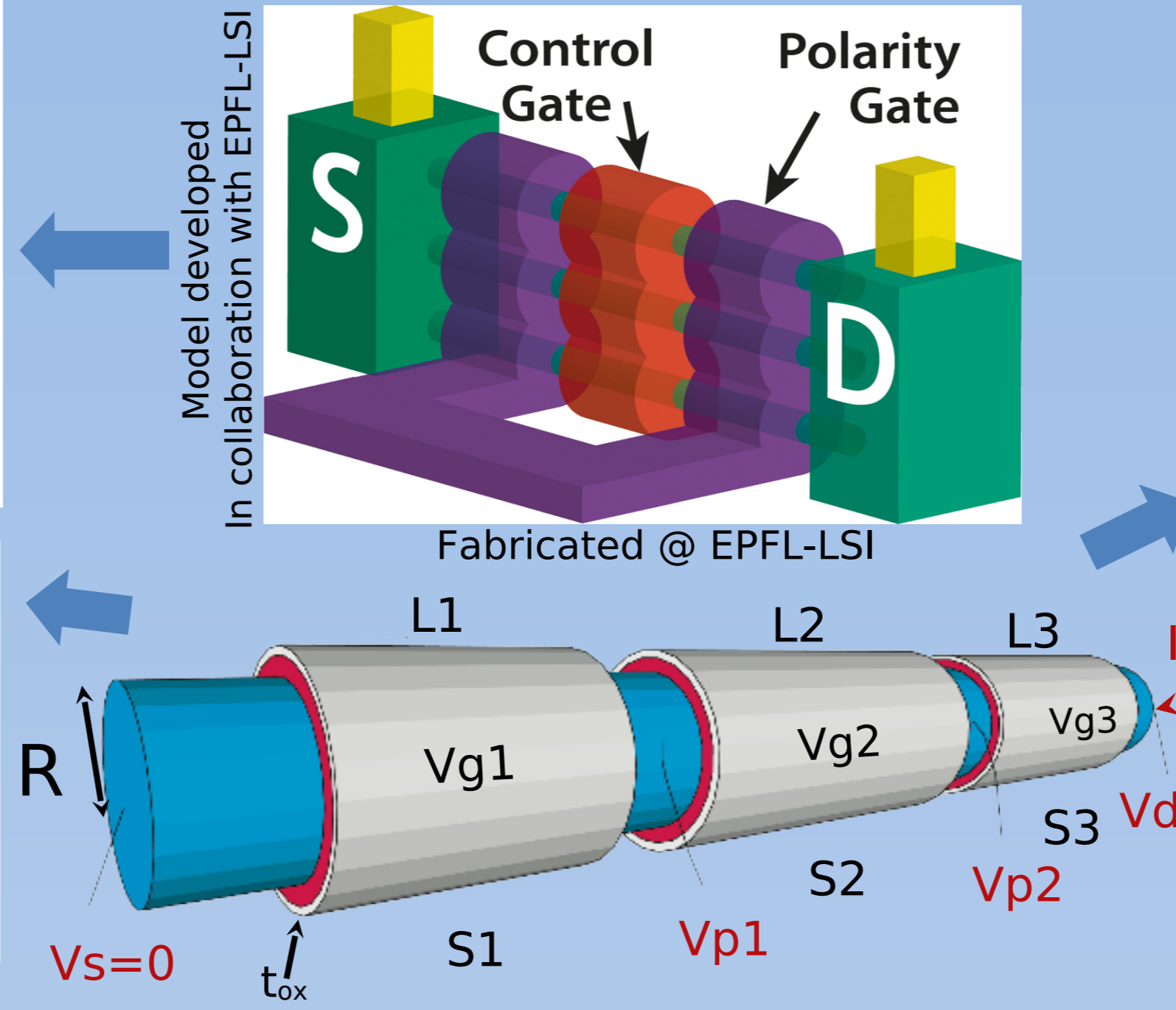
## The approach: a collective strategy.

Device is seen as composed by a series of Sections. How to **decompose** it:

Define appropriate sections ( $S_i$ ) in the overall structure.

Sections need not feature the same parameter set

The study of the complete device is reduced to the study of simpler parts



## Device section modeling

**Idea:** to study such devices with these free parameters:

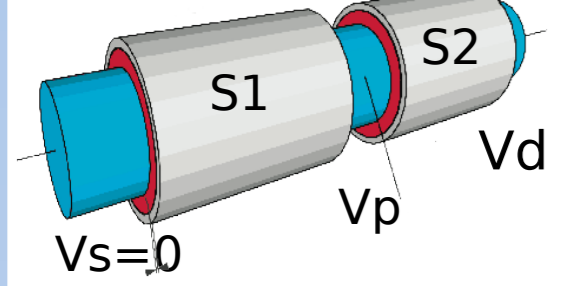
**L1, L2, L3** (different length of the sections)  
**VG1, VG2, VG3** (different applied voltages to the gates)  
**R** (radius of the nanowire) **tox** (oxide thickness)  
**I<sub>di</sub>** independently calculated in sections  $S_i$  exploiting a charge-based model  
**Hypothesis:** no voltage drop at  $S_i$  and  $S_{(i+1)}$  contacts

## Current in sections

$I_{di}$  can be calculated independently in each Section  $S_i$ , provided we know  $V_{Di}$  and  $V_{Si}$  of all sections  $V_{Di} = V_{S_{(i+1)}}$   $I_{ds_i} = I_{ds_{(i+1)}}$

Potential  $\longrightarrow$  charge density  
Charge density  $\longrightarrow$  current

## The method



$$I_{ds1} = I_{ds2}$$

$$\mu \frac{2\pi R}{L_1} \left[ 2 \frac{kT}{q} (Q_{s1} - Q_{d1}) + \frac{Q_{s1}^2 - Q_{d1}^2}{2C_{OX}} + \frac{kT}{q} Q_0 \log \left[ \frac{Q_{d1} + Q_0}{Q_{s1} + Q_0} \right] \right] =$$

$$\mu \frac{2\pi R}{L_2} \left[ 2 \frac{kT}{q} (Q_{s2} - Q_{d2}) + \frac{Q_{s2}^2 - Q_{d2}^2}{2C_{OX}} + \frac{kT}{q} Q_0 \log \left[ \frac{Q_{d2} + Q_0}{Q_{s2} + Q_0} \right] \right]$$

$Q_{d1}$  and  $Q_{d2}$  are linked with  $V_P$  and  $V_{DS}$  through the charge control eq:

$$V_{GS} - \Delta\varphi - V - \frac{kT}{q} \log \left( \frac{8}{\delta R^2} \right) = \frac{Q}{C_{ox}} + \frac{kT}{q} \log \left( \frac{Q}{Q_0} \right) + \frac{kT}{q} \log \left( \frac{Q + Q_0}{Q_0} \right)$$

$V_{s1} < V_{d1} \equiv V_P$   $V_{s2} \equiv V_P < V_{ds}$   $Q_{d1}$  and  $Q_{d2}$  can be neglected in calculating

$Q_{d1} < Q_{s1}$  and  $Q_{d2} < Q_{s2}$   $I_{ds1} = I_{ds2}$

$Q_{s2}$  can be calculated as solution of:

$$\frac{1}{2C_{OX}L_2} Q_{s2}^2 + \frac{2V_{th}}{L_2} Q_{s2} - \frac{Q_{s1}^2}{2C_{OX}L_1} - \frac{2V_{th}Q_{s1}}{L_1} = 0$$

$V_P$  can be calculated substituting  $Q_{s20}$  in the charge control equation:

$$V_{G2} - \Delta\varphi - V_P - \frac{kT}{q} \log \left( \frac{8}{\delta R^2} \right) = \frac{Q_{s20}}{C_{ox}} + \frac{kT}{q} \log \left( \frac{Q_{s20}}{Q_0} \right) + \frac{kT}{q} \log \left( \frac{Q_{s20} + Q_0}{Q_0} \right)$$

The estimate of  $V_P$  can be used to calculate  $Q_{d1}$ :

$$Q_{d1} = C_{OX} \left( -\frac{2C_{OX}V_{th}^2}{Q_0} + \sqrt{\left( \frac{2C_{OX}V_{th}^2}{Q_0} \right)^2 + 4V_{th}^2 \log^2 \left( 1 + \exp \left( \frac{V_{G1} - V_T + \Delta V_T - V_P}{2V_{th}} \right) \right)} \right)$$

Knowing  $Q_{d1}$  it is possible to calculate the current:

$$I_{DS1} = \mu \frac{2\pi R}{L_1} \left[ 2 \frac{kT}{q} (Q_{s1} - Q_{d1}) + \frac{Q_{s1}^2 - Q_{d1}^2}{2C_{OX}} + \frac{kT}{q} Q_0 \log \left[ \frac{Q_{d1} + Q_0}{Q_{s1} + Q_0} \right] \right]$$

$$I_{ds1} = I_{ds2} \quad \frac{1}{2C_{OX}} Q_{s2}^2 + 2V_{th}Q_{s2} - \frac{I_{ds1}L_2}{2\pi\mu R 2C_{OX}L_1} - \frac{Q_{s1}^2}{2C_{OX}} - 2V_{th}Q_{s1} - \frac{Q_{d2}^2}{2C_{OX}} + V_{th}Q_0 \log \left( \frac{Q_{d2} + Q_0}{Q_{s20} + Q_0} \right) = 0$$

$V_P$  can now be calculated through the charge control equation:

$$V_P = V_{G2} - \Delta\varphi - \frac{kT}{q} \log \left( \frac{8}{\delta R^2} \right) - \frac{Q_{s2}}{C_{ox}} - \frac{kT}{q} \log \left( \frac{Q_{s2}}{Q_0} \right) - \frac{kT}{q} \log \left( \frac{Q_{s2} + Q_0}{Q_0} \right)$$

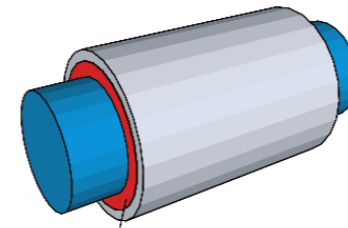
If requirements are not met it is possible to iterate the process. As a rule of thumb, the more the gates, the more iterations.

Up to three gates one iteration is enough, as will be shown in the results section. Else the process ends.

## Single section modeling

**Charge-based model** is used at Single Section level to obtain current information. Drain current calculated as:

$$I_{DS_i} = \mu \frac{2\pi R}{L} \int_0^{V_{DS_i}} Q(V_i) dV$$

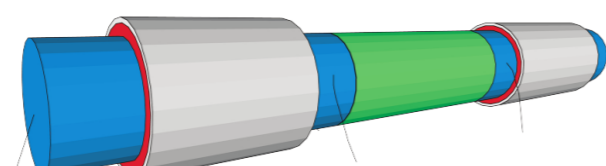


## Extensions

Same nature of the problem, same approach. slight modifications

### Gateless section

$$V_{P1} = V_{P2} - RI_{DS2}$$



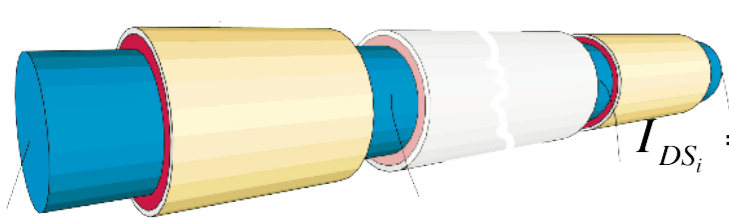
$$R = \rho \frac{L}{A} = \frac{1}{q\mu N_D} \frac{L_R}{2\pi R^2}$$

$$Q^* = Q - \alpha$$

### Doped channel

$$\psi(r) = -\delta \frac{N_A kT}{4n_i} R^2 + \delta \frac{N_A kT}{4n_i} r^2 + V + \frac{kT}{q} \log \left( \frac{-8B}{\delta(1 + Br^2)^2} \right)$$

$$\delta^* = \frac{e^{\alpha/(C_{ox}Vt)}}{N_A/n_i} \quad V_{GS} - \Delta\varphi - V - \frac{kT}{q} \log \left( \frac{8e^{\alpha/(VtC_{ox})}}{\delta \frac{N_A}{n_i} R^2} \right) = \frac{Q - \alpha}{C_{ox}} + \frac{kT}{q} \log \left( \frac{Q - \alpha}{Q_0} \right) + \frac{kT}{q} \log \left( \frac{Q - \alpha + Q_0}{Q_0} \right)$$



$$I_{DS_i} = I_{DS_i} \quad i = 2, \dots, n$$

$$\frac{1}{2C_{OX}L_i} Q_{si0}^2 + \frac{2V_{th}}{L_i} Q_{si0} - \frac{Q_{s1}^2}{2C_{OX}L_1} - \frac{2V_{th}Q_{s1}}{L_1} = 0$$

$V_{Pi}$  obtained through the charge control equation:

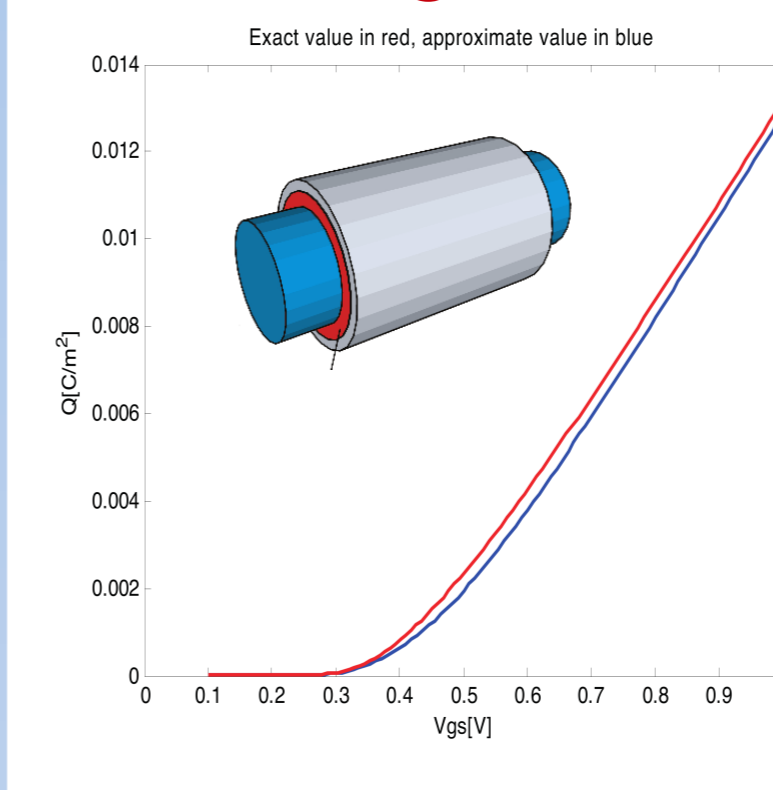
$$V_{Gi} - \Delta\varphi - V_{Pi} - \frac{kT}{q} \log \left( \frac{8}{\delta R^2} \right) = \frac{Q_{si0}}{C_{ox}} + \frac{kT}{q} \log \left( \frac{Q_{si0}}{Q_0} \right) + \frac{kT}{q} \log \left( \frac{Q_{si0} + Q_0}{Q_0} \right)$$

### Arbitrary Num. of gates

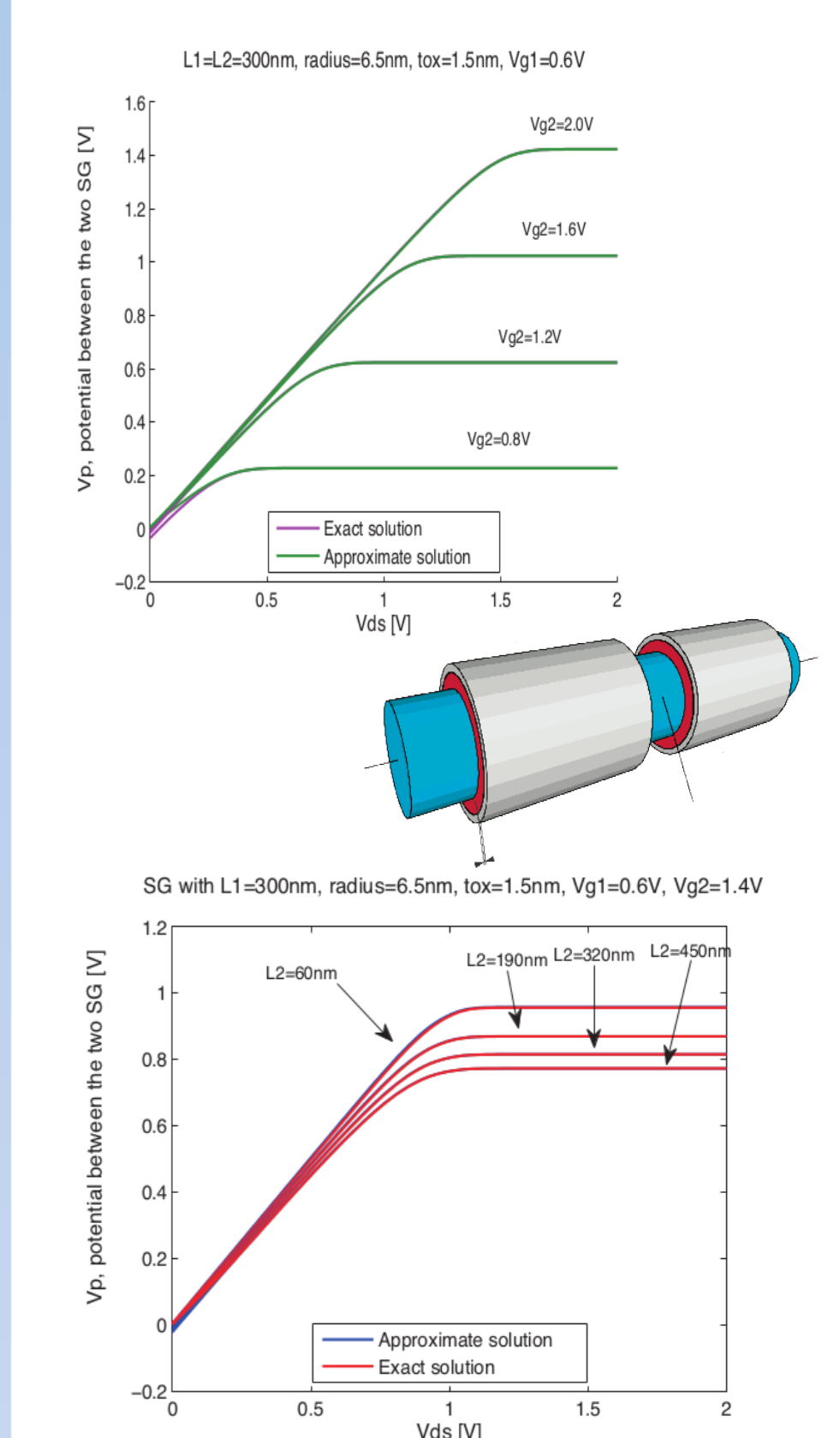
$Q_{si0}$  can be determined as positive root of:

$$Q_{di} = C_{OX} \left( -\frac{2C_{OX}V_{th}^2}{Q_0} + \sqrt{\left( \frac{2C_{OX}V_{th}^2}{Q_0} \right)^2 + 4V_{th}^2 \log^2 \left( 1 + \exp \left( \frac{V_{Gi} - V_T + \Delta V_T - V_{Pi}}{2V_{th}} \right) \right)} \right)$$

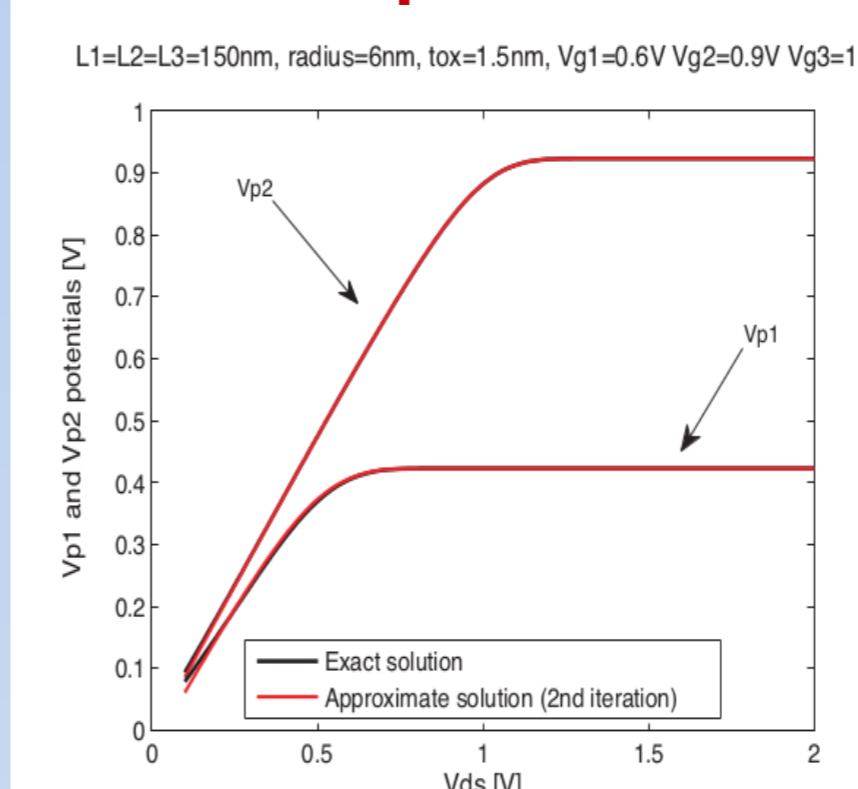
## Results: single section



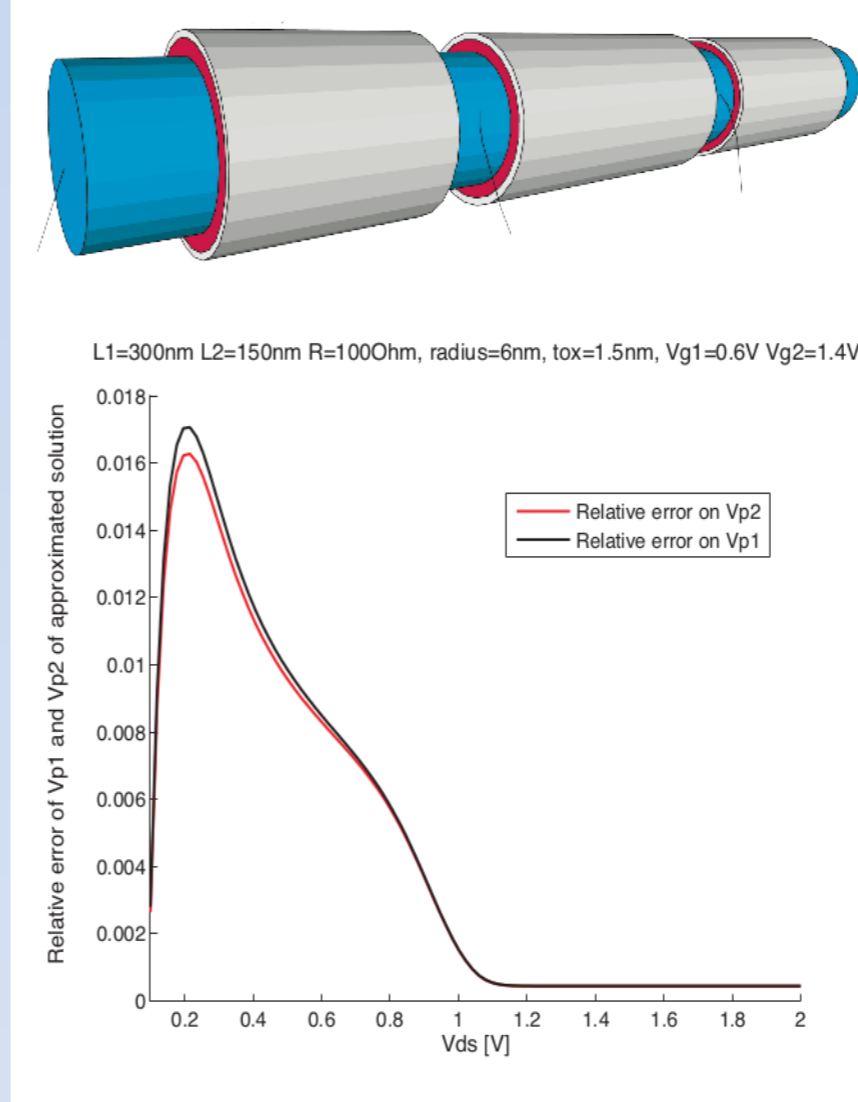
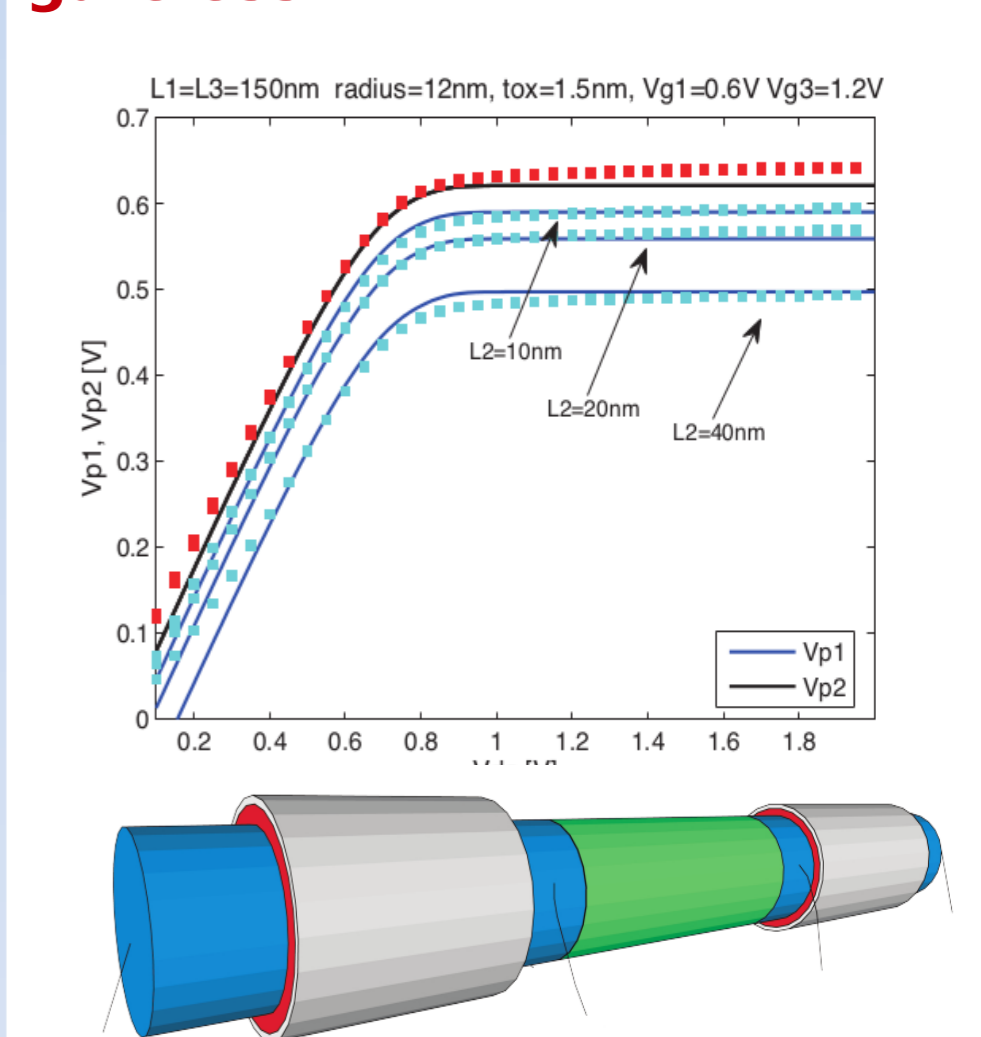
## Results: double section



## Results: triple section



## Results: triple section, one gateless



## Validation

Theoretical: numerical simulations TCAD (Silvaco Atlas)

Experimental: at this stage of development, we still did not perform this kind of verification

## Conclusions

**Fast (second vs. hours) and accurate (max err negligible) simulation**

